

<b>Notice of References Cited</b>	Application/Control No. 10/585,638		Applicant(s)/Patent Under Reexamination OHNO ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,103,315 A	07-1978	Hempstead et al.	257/E43.004
*	B	US-5,294,287 A	03-1994	Chang et al.	438/918
*	C	US-5,390,061 A	02-1995	Nakatani et al.	257/E43.004
*	D	US-5,734,605 A	03-1998	Zhu et al.	257/E21.665
*	E	US-5,768,181 A	06-1998	Zhu et al.	365/158
*	F	US-2001/0007532 A1	07-2001	Sato et al.	365/173
*	G	US-6,456,467 B1	09-2002	Mao et al.	360/319
*	H	US-2003/0209770 A1	11-2003	Flatte et al.	257/421
*	I	US-6,713,195 B2	03-2004	Wang et al.	257/E43.005
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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